

FORM PTO-1449 (Modified)				ATTY. DOCKET NO. FIS920030360US1		SERIAL NO. 10/709,406	
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT: BRODSKY ET AL.		FILING DATE:	
GROUP:				GROUP:			
REFERENCE DESIGNATION U.S. PATENT DOCUMENTS							
EXAMINER INITIALS		DOCUMENT NUMBER	ISSUED DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)							
TN	CA	S. Lee et al. "New Approach for Pattern Collapse Problem by Increasing Contact Area at Sub-100nm Patterning," Proc. SPIE – The International Society for Optical Engineering, June 2003, pp. 166-174 (Vol. 5039).					
EXAMINER /Thanh Nguyen/				DATE CONSIDERED 06/27/2006			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							